Issue Classification									

ORIGINAL

Application/Control No.	Applicant(s)/Patent under Reexamination
10/696,012	FLANDRIN ET AL.
Examiner	Art Unit
Tae H. Yoon	1714

CROSS REFERENCE(S)

CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)							
524	89	524	92	94			190	357		
INTERNATIONA	L CLASSIFICATION 7	106	401	' /		'		,		
COPK	573415		1 /					7707.04		
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			TAEH, YOON							
			TAE H. YOON PRIMARY EXAMINER					Total Claims Allowed: 36		
(Assista	nt Examiner) (Date)									
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3 5	22 35		65		95	1	125		55	185
4 7	23 36 24 37		66		96		26		56	186
7 8	25 38		67 68		97 98		27		57	187
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7 20	36 49 50		79 80		09		39		39	199
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ISSUE CLASSIFICATION